

L Number	Hits	Search Text	DB	Time stamp
1	1169	714/738.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 15:42
2	2	(714/738.ccls.) and (integrated adj circuit\$1) and semiconductor and test\$3 and (transmi\$5 with parallel with serial) and (receiv\$3 with serial with parallel) and (test\$3 with generat\$3) and compar\$5	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 15:45
3	2	(714/738.ccls.) and ((integrated adj circuit\$1) or IC) and semiconductor and test\$3 and (transmi\$5 with parallel with serial) and (receiv\$3 with serial with parallel) and (test\$3 with generat\$3) and compar\$5	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 15:43
4	15	(integrated adj circuit\$1) and semiconductor and test\$3 and (transmi\$5 with parallel with serial) and (receiv\$3 with serial with parallel) and (test\$3 with generat\$3) and compar\$5 and (test\$3 adj mode) and (loopback)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 15:47
5	2	(714/733.ccls.) and (integrated adj circuit\$1) and semiconductor and test\$3 and (transmi\$5 with parallel with serial) and (receiv\$3 with serial with parallel) and (test\$3 with generat\$3) and compar\$5	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 15:46
6	0	(713/400.ccls.) and ((integrated adj circuit\$1) or IC) and semiconductor and test\$3 and (transmi\$5 with parallel with serial) and (receiv\$3 with serial with parallel) and (test\$3 with generat\$3) and compar\$5 and (test\$3 adj mode) and (loopback)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 15:49
7	2	(375/221.ccls.) and ((integrated adj circuit\$1) or IC) and semiconductor and test\$3 and (transmi\$5 with parallel with serial) and (receiv\$3 with serial with parallel) and (test\$3 with generat\$3) and compar\$5 and (test\$3 adj mode) and (loopback)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 15:50
8	0	(324/763.ccls.) and ((integrated adj circuit\$1) or IC) and semiconductor and test\$3 and (transmi\$5 with parallel with serial) and (receiv\$3 with serial with parallel) and (test\$3 with generat\$3) and compar\$5 and (test\$3 adj mode) and (loopback)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 15:50
10	2	(370/249.ccls.) and ((integrated adj circuit\$1) or IC) and semiconductor and test\$3 and (transmi\$5 with parallel with serial) and (receiv\$3 with serial with parallel) and (test\$3 with generat\$3) and compar\$5 and (test\$3 adj mode) and (loopback)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 15:51